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# CMOS Circuit Characteristics Formulas

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# List of 15 CMOS Circuit Characteristics Formulas

## CMOS Circuit Characteristics

### 1) Area of Source Diffusion

$$fx \quad A_s = D_s \cdot W$$

Open Calculator 

$$ex \quad 5479.02\text{mm}^2 = 61\text{mm} \cdot 89.82\text{mm}$$

### 2) CMOS Critical Voltage

$$fx \quad V_c = E_c \cdot L$$

Open Calculator 

$$ex \quad 2.79028\text{V} = 0.004\text{V}/\text{mm} \cdot 697.57\text{mm}$$

### 3) CMOS Mean Free Path

$$fx \quad L = \frac{V_c}{E_c}$$

Open Calculator 

$$ex \quad 697.5\text{mm} = \frac{2.79\text{V}}{0.004\text{V}/\text{mm}}$$



#### 4) Critical Electric Field

$$fx \quad E_c = \frac{2 \cdot V_{sat}}{\mu_e}$$

[Open Calculator !\[\]\(cbe80b694ebd74fcfe136a095b608235\_img.jpg\)](#)

$$ex \quad 0.004064V/mm = \frac{2 \cdot 10.12mm/s}{49.8cm^2/V*s}$$

#### 5) Depletion Region Width

$$fx \quad L_d = L_{pn} - L_{eff}$$

[Open Calculator !\[\]\(3e2231b1ad3ca8da8658228c00dd08e0\_img.jpg\)](#)

$$ex \quad 11mm = 19mm - 8mm$$

#### 6) Effective Capacitance in CMOS

$$fx \quad C_{eff} = D \cdot \frac{i_{off} \cdot (10^{V_{bc}})}{N_g \cdot [BoltZ] \cdot V_{bc}}$$

[Open Calculator !\[\]\(0d5ec72f61334709c3fc9450209b754f\_img.jpg\)](#)

$$ex \quad 5.137895\mu F = 1.3E^{-25} \cdot \frac{0.01mA \cdot (10^{2.02V})}{0.95 \cdot [BoltZ] \cdot 2.02V}$$

#### 7) Effective Channel Length

$$fx \quad L_{eff} = L_{pn} - L_d$$

[Open Calculator !\[\]\(b64b40baaee5acddc1eab8538ba84754\_img.jpg\)](#)

$$ex \quad 7.99mm = 19mm - 11.01mm$$



## 8) Oxide Layer Thickness

$$fx \quad t_{ox} = \epsilon_{ox} \cdot W_g \cdot \frac{L_g}{C_{in}}$$

[Open Calculator !\[\]\(e78f798d4ea5c530c9db49e7d26e6b95\_img.jpg\)](#)

$$ex \quad 4.979688mm = 149.79\mu F/mm \cdot 0.285mm \cdot \frac{7mm}{60.01\mu F}$$

## 9) Permittivity of Oxide Layer

$$fx \quad \epsilon_{ox} = t_{ox} \cdot \frac{C_{in}}{W_g \cdot L_g}$$

[Open Calculator !\[\]\(05be7c7a8995decd503647c99211f7c2\_img.jpg\)](#)

$$ex \quad 149.7994\mu F/mm = 4.98mm \cdot \frac{60.01\mu F}{0.285mm \cdot 7mm}$$

## 10) PN Junction Length

$$fx \quad L_{pn} = L_d + L_{eff}$$

[Open Calculator !\[\]\(fe3aebe81acea8d45108cd2768939da7\_img.jpg\)](#)

$$ex \quad 19.01mm = 11.01mm + 8mm$$

## 11) Sidewall Perimeter of Source Diffusion

$$fx \quad P_s = (2 \cdot W) + (2 \cdot D_s)$$

[Open Calculator !\[\]\(899d8b7697d64725bf017d3296cfcf1b\_img.jpg\)](#)

$$ex \quad 301.64mm = (2 \cdot 89.82mm) + (2 \cdot 61mm)$$



12) Transition Width of CMOS 

$$fx \quad W = \frac{C_{mos}}{C_{gs}}$$

Open Calculator 


$$ex \quad 89.82036mm = \frac{1.8\mu F}{20.04\mu F}$$

13) Voltage at Minimum EDP 

$$fx \quad V_{edp} = \frac{3 \cdot V_t}{3 - \alpha}$$

Open Calculator 


$$ex \quad 0.666667V = \frac{3 \cdot 0.3V}{3 - 1.65}$$

14) Width of Gate 

$$fx \quad W_g = \frac{C_{in}}{C_{ox} \cdot L_g}$$

Open Calculator 

$$ex \quad 0.285667mm = \frac{60.01\mu F}{30.01\mu F/mm^2 \cdot 7mm}$$

15) Width of Source Diffusion 

$$fx \quad W = \frac{A_s}{D_s}$$

Open Calculator 

$$ex \quad 89.81967mm = \frac{5479mm^2}{61mm}$$



## Variables Used











- $\mu_e$  Mobility of Electron (Square Centimeter per Volt Second)
- $A_s$  Area of Source Diffusion (Square Millimeter)
- $C_{\text{eff}}$  Effective Capacitance in CMOS (Microfarad)
- $C_{\text{gs}}$  MOS Gate Capacitance (Microfarad)
- $C_{\text{in}}$  Input Gate Capacitance (Microfarad)
- $C_{\text{mos}}$  MOS Gate Overlap Capacitance (Microfarad)
- $C_{\text{ox}}$  Capacitance of Gate Oxide Layer (Microfarad per Square Millimeter)
- $D$  Duty Cycle
- $D_s$  Length of Source (Millimeter)
- $E_c$  Critical Electric Field (Volt per Millimeter)
- $i_{\text{off}}$  Off Current (Milliampere)
- $L$  Mean Free Path (Millimeter)
- $L_d$  Depletion Region Width (Millimeter)
- $L_{\text{eff}}$  Effective Channel Length (Millimeter)
- $L_g$  Length of Gate (Millimeter)
- $L_{\text{pn}}$  PN Junction Length (Millimeter)
- $N_g$  Gates on Critical Path
- $P_s$  Sidewall Perimeter of Source Diffusion (Millimeter)
- $t_{\text{ox}}$  Oxide Layer Thickness (Millimeter)
- $V_{\text{bc}}$  Base Collector Voltage (Volt)
- $V_c$  Critical Voltage in CMOS (Volt)



- $V_{edp}$  Voltage at Minimum EDP (Volt)
- $V_{sat}$  Velocity Saturation (Millimeter per Second)
- $V_t$  Threshold Voltage (Volt)
- $W$  Transition Width (Millimeter)
- $W_g$  Gate Width (Millimeter)
- $\alpha$  Activity Factor
- $\epsilon_{ox}$  Permittivity of Oxide Layer (Microfarad per Millimeter)





## Constants, Functions, Measurements used

- **Constant:** [**BoltZ**],  $1.38064852E-23$  Joule/Kelvin  
*Boltzmann constant*
- **Measurement: Length** in Millimeter (mm)  
*Length Unit Conversion* 
- **Measurement: Electric Current** in Milliampere (mA)  
*Electric Current Unit Conversion* 
- **Measurement: Area** in Square Millimeter ( $\text{mm}^2$ )  
*Area Unit Conversion* 
- **Measurement: Speed** in Millimeter per Second (mm/s)  
*Speed Unit Conversion* 
- **Measurement: Capacitance** in Microfarad ( $\mu\text{F}$ )  
*Capacitance Unit Conversion* 
- **Measurement: Electric Field Strength** in Volt per Millimeter (V/mm)  
*Electric Field Strength Unit Conversion* 
- **Measurement: Electric Potential** in Volt (V)  
*Electric Potential Unit Conversion* 
- **Measurement: Mobility** in Square Centimeter per Volt Second ( $\text{cm}^2/\text{V}^*\text{s}$ )  
*Mobility Unit Conversion* 
- **Measurement: Oxide Capacitance Per Unit Area** in Microfarad per Square Millimeter ( $\mu\text{F}/\text{mm}^2$ )  
*Oxide Capacitance Per Unit Area Unit Conversion* 
- **Measurement: Permittivity** in Microfarad per Millimeter ( $\mu\text{F}/\text{mm}$ )  
*Permittivity Unit Conversion* 





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- [Array Datapath Subsystem Formulas](#) 
- [CMOS Circuit Characteristics Formulas](#) 
- [CMOS Delay Characteristics Formulas](#) 
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